

Application/Control No.	Applicant(s)/Patent under Reexamination
10/626,787	LEEK, WILLIAM F.
Examiner	Art Unit
Phi D. A	3637

SEARCHED						
Subclass	Date		Examiner			
441	7/11/2006			PA		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
16-2					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)						
	DATE	EXMR				
search from parent case 09/729491 updated	7/11/2006					
Neil Wilson 411/231*, 432, 917* updated search from parent case	7/11/2006					